

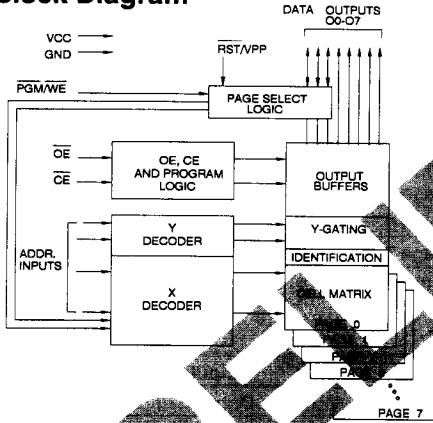
Features

- Paged Configurations with Page Reset on Power-Up or $\overline{\text{RST}}$ Signal
8 Pages, 16K x 8
- Low Power CMOS Operation
100 μA max. Standby
25 mA max. Active at 5 MHz
- Fast Read Access Time - 150ns
- Wide Selection of JEDEC Standard Packages Including OTP
28-Lead 600 mil Cerdip and OTP Plastic DIP
32-Pad LCC and OTP PLCC
- 5V \pm 10% Supply
- High Reliability CMOS Technology
2000V ESD Protection
200mA Latchup Immunity
- Rapid Programming - 100 μs /byte (typical)
- Two-line Control
- CMOS and TTL Compatible Inputs and Outputs
- Integrated Product Identification Code
- Military, Commercial and Industrial Temperature Ranges
- Fully Compatible with 27128, 27513, 27011

**1 MEGABIT
(8 x 16K x 8)
UV
Erasable
Programmable
CMOS
EPROM**

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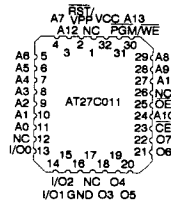
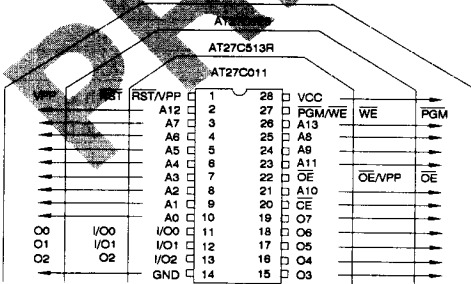
Block Diagram



| Address Range | Number of Pages | Bits per Page |
|---------------------|-----------------|---------------|
| 00000000 - 00000007 | 1 | 131,072 |

| Pin Name | Function |
|-----------|-------------------|
| A0-A7 | Addresses |
| Y0-Y7 | Outputs |
| I/O0-I/O1 | Input/Output |
| CE | Chip Enable |
| OE | Output Enable |
| PGM/WE | Page Write Enable |
| RST/VPP | Page Reset |
| NC | No Connect |

Pin Configurations



Note: JEDEC standard pinouts for AT27C513R and AT27C128 are shown for comparison only.

Note: PLCC Package Pins 1 and 17 are DON'T CONNECT.

Preliminary





Description

The AT27C011 is a low-power, high performance 1,048,576 bit Ultraviolet Erasable and Electrically Programmable Read Only Memory (EPROM). This device requires only one 5V power supply in normal read mode operation. Any byte can be accessed in less than 150ns, making this part compatible with high performance microprocessor systems by eliminating the need for speed-reducing WAIT states.

The AT27C011 features page mode addressing. Atmel's 27C011 has 8 pages, each organized 16K x 8, and provides a compatible upgrade for existing 128K EPROM based designs. Increased memory capacity and improved system performance can now be easily retrofitted without using costly additional board space.

The AT27C011 has an automatic page latch clear circuit to ensure consistent page selection during system bootstrapping. The page latches are automatically reset to page 0 upon power-up (resets typically for $V_{CC} \leq 3.8V$) or when RST/Vpp is brought low (V_{IL}).

Atmel's 1.2 micron scaled CMOS technology provides significantly lower active power consumption than similar NMOS designs. Power consumption is typically only 8mA in Active Mode and less than 20 μ A in Standby.

The AT27C011 is available in a choice of industry standard JEDEC-approved packages including; 28-pin DIP in ceramic or one time programmable (OTP) plastic, and 32-pad ceramic leadless chip carrier (LCC) or OTP plastic J-leaded chip carrier (PLCC). All devices feature two line control ($\overline{CE}, \overline{OE}$) to give designers the flexibility to prevent bus contention.

With a high density 128K byte storage capability, the AT27C011 allows firmware to be stored reliably and to be quickly accessed by the system without the delays of mass storage media.

The AT27C011 has additional features to ensure high quality and efficient production use. The rapid programming algorithm reduces the time required to program the chip and guarantees reliable programming. Programming time is typically 100 μ s/byte. The Integrated Product Identification Code electronically identifies the device and manufacturing origin. This feature is used by industry standard programming equipment to select the proper programming algorithms and voltages.

Page Selection Data ⁽¹⁾

| Page Selection | Page DIN | | | Page Selection | Page DIN | | |
|----------------|-----------------|-----------------|-----------------|----------------|-----------------|-----------------|-----------------|
| | I/O2 | I/O1 | I/O0 | | I/O2 | I/O1 | I/O0 |
| Select Page 0 | V _{IL} | V _{IL} | V _{IL} | Select Page 4 | V _{IH} | V _{IL} | V _{IL} |
| Select Page 1 | V _{IL} | V _{IL} | V _{IH} | Select Page 5 | V _{IH} | V _{IL} | V _{IH} |
| Select Page 2 | V _{IL} | V _{IH} | V _{IL} | Select Page 6 | V _{IH} | V _{IH} | V _{IL} |
| Select Page 3 | V _{IL} | V _{IH} | V _{IH} | Select Page 7 | V _{IH} | V _{IH} | V _{IH} |

Note: 1. The AT27C011 automatically resets to page 0 whenever $V_{CC} \leq 3.8V$ (typical conditions).

Operating Modes

| MODE \ PIN | \overline{CE} | \overline{OE} | PGM/WE | RST/VPP | Ai | V_{CC} ⁽³⁾ | Outputs | I/Oi |
|---------------------------------------|-----------------|-----------------|-----------------|-----------------|---|-------------------------|---------------------|---------------------|
| Read | V _{IL} | V _{IL} | V _{IH} | V _{IH} | Ai | V_{CC} | DOUT | DOUT |
| Output Disable | V _{IL} | V _{IH} | V _{IH} | V _{IH} | X ⁽¹⁾ | V_{CC} | High Z | High Z |
| Standby | V _{IH} | X | X | X | X | V_{CC} | High Z | High Z |
| Rapid Program ⁽²⁾ | V _{IL} | V _{IH} | V _{IL} | V _{PP} | Ai | V_{CC} | DIN | DIN |
| PGM Verify | V _{IL} | V _{IL} | V _{IH} | V _{PP} | Ai | V_{CC} | DOUT | DOUT |
| PGM Inhibit | V _{IH} | X | V _{IH} | V _{PP} | X | V_{CC} | High Z | High Z |
| Page Select | V _{IL} | V _{IH} | V _{IL} | V _{IH} | X | V_{CC} ⁽³⁾ | High Z | Page DIN |
| Page Reset | X | X | X | V _{IL} | X | V_{CC} ⁽³⁾ | High Z | High Z |
| Product Identification ⁽⁵⁾ | V _{IL} | V _{IL} | V _{IH} | V _{IH} | A9=V _H ⁽⁴⁾ A0=V _{IH} or V _{IL} A1-A13=V _{IL} | V_{CC} | Identification Code | Identification Code |

Notes: 1. X can be V_{IL} or V_{IH}.

2. Refer to Programming characteristics.

3. Page 0 is automatically selected at power up ($V_{CC} < 3.8V$).

4. $V_H = 12.0 \pm 0.5V$.

5. Two identifier bytes may be selected. All Ai inputs

are held low (V_{IL}), except A9 which is set to V_{IH} and A0 which is toggled low (V_{IL}) to select the Manufacturer's Identification byte and high (V_{IH}) to select the Device Code byte.

Absolute Maximum Ratings*

| | |
|---|---|
| Temperature Under Bias | -55°C to +125°C |
| Storage Temperature | -65°C to +150°C |
| Voltage on Any Pin with Respect to Ground | -2.0V to +7.0V ⁽¹⁾ |
| Voltage on A9 with Respect to Ground | -2.0V to +14.0V ⁽¹⁾ |
| V _{PP} Supply Voltage with Respect to Ground | -2.0V to +14.0V ⁽¹⁾ |
| Integrated UV Erase Dose..... | 7258 w _a sec/cm ² |

*NOTICE: Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

- Notes:
 1. Minimum voltage is -0.6V dc which may undershoot to -2.0V for pulses of less than 20ns. Maximum output pin voltage is V_{CC}+0.75V dc which may overshoot to +7.0V for pulses of less than 20ns.

D.C. and A.C. Operating Conditions for Read and Page Select Operations

| AT27C011 | | | | | |
|------------------------------|------|------------|---------------|---------------|---------------|
| | | -15 | -17 | -20 | -25 |
| Operating Temperature (Case) | Com. | 0°C - 70°C | 0°C - 70°C | 0°C - 70°C | 0°C - 70°C |
| | Ind. | | -40°C - 85°C | -40°C - 85°C | -40°C - 85°C |
| | Mil. | | -55°C - 125°C | -55°C - 125°C | -55°C - 125°C |
| V _{CC} Power Supply | | 5V ± 5% | 5V ± 10% | 5V ± 10% | 5V ± 10% |

D.C. and Operating Characteristics for Read and Page Select Operations

| Symbol | Parameter | Condition | Min | Max | Units |
|------------------|--|--|----------------------|---------------------|-------|
| I _{LI} | Input Load Current | V _{IN} = -0.1V to V _{CC} + 1V | | 5 | μA |
| I _{LO} | Output Leakage Current | V _{OUT} = -0.1V to V _{CC} + 0.1V | | 10 | μA |
| I _{PP1} | R _{ST} /V _{PP} ⁽¹⁾ Read/Standby Current | R _{ST} /V _{PP} = 3.8 to V _{CC} + 0.3V | | 10 | μA |
| I _{SB} | V _{CC} ⁽¹⁾ Standby Current | I _{SB1} (CMOS) CE = V _{CC} -0.3 to V _{CC} + 1.0V | | 100 | μA |
| | | I _{SB2} (TTL) CE = 2.0 to V _{CC} + 1.0V | | 1 | mA |
| I _{CC} | V _{CC} Active Current | f = 5MHz, I _{OUT} = 0mA, CE = V _{IL} | Com. | 25 | mA |
| | | | Ind., Mil. | 30 | mA |
| V _{IL} | Input Low Voltage | | -0.6 | 0.8 | V |
| V _{IH} | Input High Voltage | | 2.0 | V _{CC} + 1 | V |
| V _{OL} | Output Low Voltage | I _{OL} = 2.1mA | | .45 | V |
| | | I _{OH} = -100μA | V _{CC} -0.3 | | V |
| V _{OH} | Output High Voltage | I _{OH} = -2.5mA | | 3.5 | V |
| | | I _{OH} = -400μA | | 2.4 | V |
| | | | | | |
| V _{CLR} | Page Latch Clear V _{CC} Supply Voltage | | | 4.0 | V |

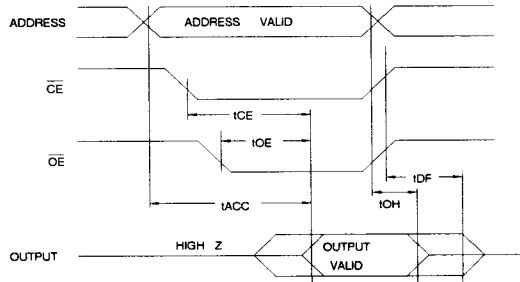
Notes: 1. V_{CC} must be applied simultaneously or before R_{ST}/V_{PP}, and removed simultaneously or after R_{ST}/V_{PP}.



A.C. Characteristics for Read Operation

| Symbol | Parameter | Condition | AT27C011 | | | | | | | | Units |
|-----------------------|---|---|------------|-----|-----|-----|-----|-----|-----|-----|-------|
| | | | -15 | | -17 | | -20 | | -25 | | |
| | | | Min | Max | Min | Max | Min | Max | Min | Max | |
| t _{ACC} (4) | Address to Output Delay | $\overline{CE} = \overline{OE}$ $= V_{IL}$ | Com. | 150 | | 170 | | 200 | | 250 | ns |
| | | | Ind., Mil. | | | 170 | | 200 | | 250 | ns |
| t _{CE} (3) | \overline{CE} to Output Delay, $\overline{OE} = V_{IL}$ | | | 150 | | 170 | | 200 | | 250 | ns |
| t _{OE} (3,4) | \overline{OE} to Output Delay | $\overline{CE} = V_{IL}$ | | 65 | | 70 | | 75 | | 100 | ns |
| t _{DF} (2,5) | \overline{OE} or \overline{CE} High to Output Float | $\overline{CE} = V_{IL}$ | | 50 | | 55 | | 55 | | 60 | ns |
| t _{OH} | Output Hold from Address, \overline{CE} or \overline{OE} , whichever occurred first | $\overline{CE} = \overline{OE}$ $= V_{IL}$ | | 0 | | 0 | | 0 | | 0 | ns |

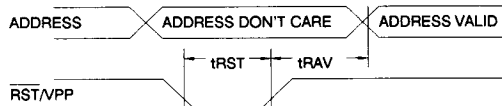
A.C. Waveforms for Read Operation (1)



Notes:

- Timing measurement references are 0.8V and 2.0V. Input AC driving levels are 0.45V and 2.4V, unless otherwise specified.
- t_{DF} is specified from \overline{OE} or \overline{CE} , whichever occurs first. Output float is defined as the point when data is no longer driven.
- \overline{OE} may be delayed up to t_{CE}-t_{OE} after the falling edge of \overline{CE} without impact on t_{CE}.
- \overline{OE} may be delayed up to t_{ACC}-t_{OE} after the address is valid without impact on t_{ACC}.
- This parameter is only sampled and is not 100% tested.

A.C. Waveforms for Page Reset Operation



Pin Capacitance (f = 1MHz T = 25°C) (1)

| | Typ | Max | Units | Conditions |
|------------------|-----|-----|-------|-----------------------|
| C _{IN} | 4 | 6 | pF | V _{IN} = 0V |
| C _{OUT} | 8 | 12 | pF | V _{OUT} = 0V |

Notes: 1. Typical values for nominal supply voltage. This parameter is only sampled and is not 100% tested.

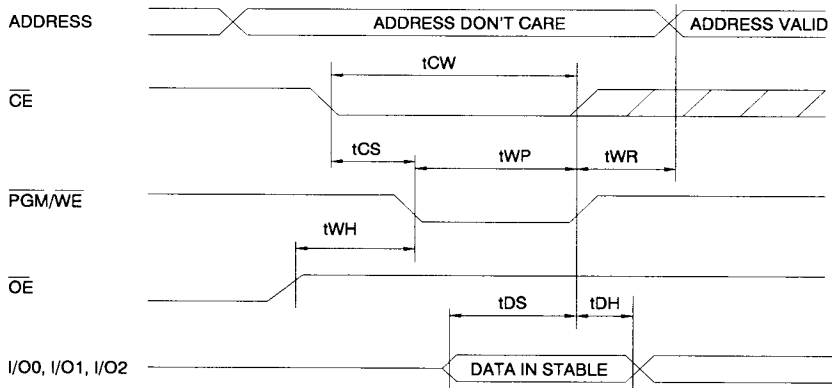
A.C. Characteristics for Page Select and Page Reset Operations

| Symbol | Parameter | Condition | AT27C011 | | | | | | | | Units |
|----------------------------------|---|--------------------------|----------|-----|-----|-----|-----|-----|-----|-----|-------|
| | | | -15 | | -17 | | -20 | | -25 | | |
| | | | Min | Max | Min | Max | Min | Max | Min | Max | |
| t _{CW} ⁽¹⁾ | \overline{CE} to End of Write | $\overline{OE} = V_{IH}$ | 110 | | 125 | | 145 | | 180 | | ns |
| t _{WP} ⁽¹⁾ | Write Pulse Width | $\overline{OE} = V_{IH}$ | 60 | | 70 | | 80 | | 100 | | ns |
| t _{WR} ⁽³⁾ | Write Recovery Time | | 20 | | 20 | | 20 | | 20 | | ns |
| t _{DS} | Data Setup Time | $\overline{OE} = V_{IH}$ | 35 | | 40 | | 45 | | 50 | | ns |
| t _{DH} | Data Hold Time | $\overline{OE} = V_{IH}$ | 20 | | 20 | | 20 | | 20 | | ns |
| t _{CS} | \overline{CE} to Write Setup Time | $\overline{OE} = V_{IH}$ | 0 | | 0 | | 0 | | 0 | | ns |
| t _{WH} ^(2,3) | PGM/ \overline{WE} Low from \overline{OE} High Delay Time | | 50 | | 50 | | 50 | | 55 | | ns |
| t _{RST} | Reset Low Time | | 150 | | 170 | | 200 | | 250 | | ns |
| t _{RAV} | Reset to Address Valid | | 150 | | 170 | | 200 | | 250 | | ns |

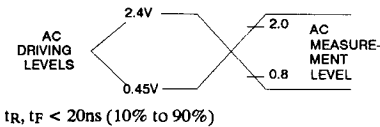
- Notes: 1. Writing can be terminated by either \overline{CE} or PGM/ \overline{WE} going high after the minimum t_{CW} or t_{WP} requirements have been met.
 2. \overline{OE} must be at V_{IH} during a Page Select.
 3. This parameter is only sampled and is not 100% tested.

4

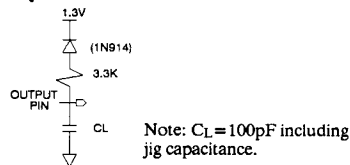
A.C. Waveforms for Page Select Operation



Input Test Waveforms and Measurement Levels



Output Test Load





D.C. Programming Characteristics

$T_A=25\pm 5^\circ\text{C}$, $V_{CC}=6.5\pm 0.25\text{V}$, $\overline{\text{RST}}/\overline{\text{VPP}}=13.0\pm 0.25\text{V}$

| Sym- bol | Parameter | Test Conditions | Limits | | Units |
|------------------|--|---|--------|--------------|---------------|
| | | | Min | Max | |
| I _{LI} | Input Load Current | $V_{IN} = V_{IL}, V_{IH}$ | | 10 | μA |
| V _{IL} | Input Low Level | (All Inputs) | -0.6 | 0.8 | V |
| V _{IH} | Input High Level | | 2.0 | $V_{CC} + 1$ | V |
| V _{OL} | Output Low Volt. | $I_{OL} = 2.1\text{mA}$ | | .45 | V |
| V _{OH} | Output High Volt. | $I_{OH} = -400\mu\text{A}$ | 2.4 | | V |
| I _{CC2} | V _{CC} Supply Current (Program and Verify) | | | 25 | mA |
| I _{PP2} | $\overline{\text{RST}}/\overline{\text{VPP}}$ Current | $\overline{\text{CE}} = \overline{\text{PGM}}/\overline{\text{WE}}$ $= V_{IL}$ | | 20 | mA |
| V _{ID} | A9 Product Identification Voltage | | 11.5 | 12.5 | V |

*A.C. Conditions of Test:

Input Rise and Fall Times (10% to 90%) 20ns
 Input Pulse Levels 0.45V to 2.4V
 Input Timing Reference Level 0.8V to 2.0V
 Output Timing Reference Level 0.8V to 2.0V

A.C. Programming Characteristics

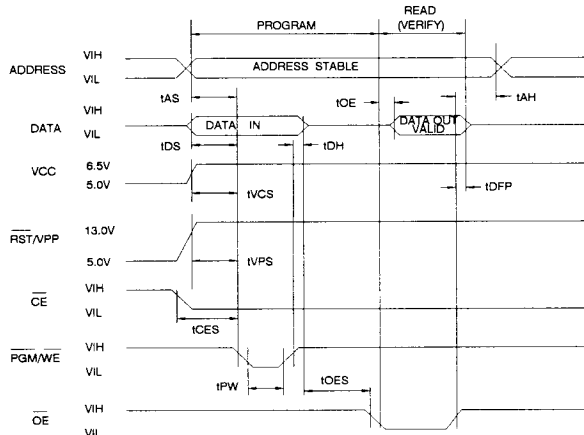
$T_A=25\pm 5^\circ\text{C}$, $V_{CC}=6.5\pm 0.25\text{V}$, $\overline{\text{RST}}/\overline{\text{VPP}}=13.0\pm 0.25\text{V}$

| Sym- bol | Parameter | Test Conditions* (see Note 1) | Limits | | Units |
|------------------|--|-------------------------------------|--------|-----|---------------|
| | | | Min | Max | |
| t _{AS} | Address Setup Time | | 2 | | μs |
| t _{CES} | $\overline{\text{CE}}$ Setup Time | | 2 | | μs |
| t _{OES} | $\overline{\text{OE}}$ Hold Time | | 2 | | μs |
| t _{DS} | Data Setup Time | | 2 | | μs |
| t _{AH} | Address Hold Time | | 0 | | μs |
| t _{DH} | Data Hold Time | | 2 | | μs |
| t _{DFP} | $\overline{\text{OE}}$ High to Out- put Float Delay | (Note 2) | 0 | 130 | ns |
| t _{VPS} | $\overline{\text{RST}}/\overline{\text{VPP}}$ Setup Time | | 2 | | μs |
| t _{VCS} | V _{CC} Setup Time | | 2 | | μs |
| t _{PW} | $\overline{\text{PGM}}/\overline{\text{WE}}$ Program Pulse Width | (Note 3) | 95 | 105 | μs |
| t _{OE} | Data Valid from $\overline{\text{OE}}$ | | | 150 | ns |

Notes:

- V_{CC} must be applied simultaneously or before $\overline{\text{RST}}/\overline{\text{VPP}}$ and removed simultaneously or after $\overline{\text{RST}}/\overline{\text{VPP}}$.
- This parameter is only sampled and is not 100% tested. Output Float is defined as the point where data is no longer driven — see timing diagram.
- Program Pulse width tolerance is $100\mu\text{sec} \pm 5\%$.

Programming Waveforms ⁽¹⁾



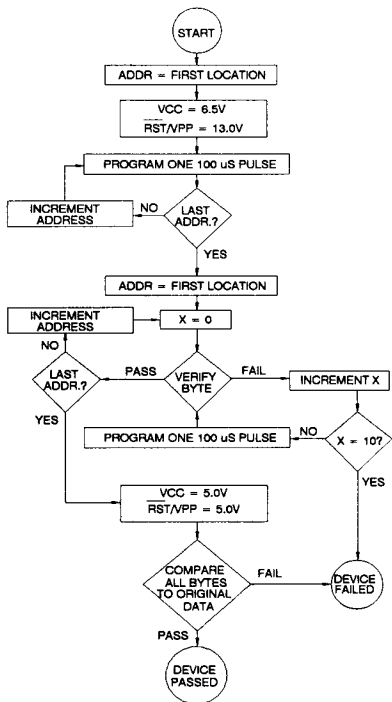
Notes:

- The Input Timing Reference is 0.8V for V_{IL} and 2.0V for V_{IH}.
- t_{DP} and t_{DFP} are characteristics of the device but must be accommodated by the programmer.
- The proper page to be programmed must be selected by a page select operation prior to programming the AT27C011.

Rapid Programming Algorithm ⁽¹⁾

A 100µs PGM/WE pulse width is used to program. The address is set to the first location. VCC is raised to 6.5V and RST/Vpp is raised to 13.0V. Each address is first programmed with one 100µs PGM/WE pulse without verification. Then a verification/reprogramming loop is executed for each address. In the event a byte fails to pass verification, up to 10 successive 100µs pulses are applied with a verification after each pulse. If the byte fails to verify after 10 pulses have been applied, the part is considered failed. After the byte verifies properly, the next address is selected until all have been checked. RST/Vpp is then lowered to 5.0V and VCC to 5.0V. All bytes are read again and compared with the original data to determine if the device passes or fails.

Note: 1. The proper page to be programmed must be selected by a page select operation prior to programming the AT27C011.



Erase Characteristics

The entire memory array of the AT27C011 is erased (all outputs read as VOH) after exposure to ultraviolet light at a wavelength of 2537 Å. Complete erasure is assured after a minimum of 20 minutes exposure using 12,000µW/cm² intensity lamps spaced one inch away from the chip. Minimum erase time for lamps at other intensity ratings can be calculated from the minimum integrated erasure dose of 15W•sec/cm². To prevent unintentional erasure, an opaque label is recommended to cover the clear window on any UV erasable EPROM which will be subjected to continuous fluorescent indoor lighting or sunlight.

4

Identification Code:

| Codes | Pins | | | | | | | | | Hex Data |
|--------------|------|----|----|----|----|----|----|----|----|----------|
| | A0 | O7 | O6 | O5 | O4 | O3 | O2 | O1 | O0 | |
| Manufacturer | 0 | 0 | 0 | 0 | 1 | 1 | 1 | 1 | 0 | 1E |
| Device Type | 1 | 1 | 0 | 0 | 0 | 0 | 1 | 0 | 1 | 85 |





Ordering Information

| t _{ACC} (ns) | I _{CC} (mA) | | Ordering Code | Package | Operation Range |
|--------------------------|----------------------|---------|--|------------------------------|---|
| | Active | Standby | | | |
| 150 | 25 | 0.1 | AT27C011-15DC AT27C011-15LC | 28DW6 32LW | Commercial (0°C to 70°C) |
| 170 | 25 | 0.1 | AT27C011-17DC AT27C011-17LC AT27C011-17PC AT27C011-17JC | 28DW6 32LW 28P6 32J | Commercial (0°C to 70°C) |
| 170 | 30 | 0.1 | AT27C011-17DI AT27C011-17LI AT27C011-17PI AT27C011-17JI | 28DW6 32LW 28P6 32J | Industrial (-40°C to 85°C) |
| | | | AT27C011-17DM AT27C011-17LM | 28DW6 32LW | Military (-55°C to 125°C) |
| | | | AT27C011-17DM/883 AT27C011-17LM/883 | 28DW6 32LW | Military/883C Class B, Fully Compliant (-55°C to 125°C) |
| 200 | 25 | 0.1 | AT27C011-20DC AT27C011-20LC AT27C011-20PC AT27C011-20JC | 28DW6 32LW 28P6 32J | Commercial (0°C to 70°C) |
| 200 | 30 | 0.1 | AT27C011-20DI AT27C011-20LI AT27C011-20PI AT27C011-20JI | 28DW6 32LW 28P6 32J | Industrial (-40°C to 85°C) |
| | | | AT27C011-20DM AT27C011-20LM | 28DW6 32LW | Military (-55°C to 125°C) |
| | | | AT27C011-20DM/883 AT27C011-20LM/883 | 28DW6 32LW | Military/883C Class B, Fully Compliant (-55°C to 125°C) |
| 250 | 25 | 0.1 | AT27C011-25DC AT27C011-25LC AT27C011-25PC AT27C011-25JC | 28DW6 32LW 28P6 32J | Commercial (0°C to 70°C) |
| 250 | 30 | 0.1 | AT27C011-25DI AT27C011-25LI AT27C011-25PI AT27C011-25JI | 28DW6 32LW 28P6 32J | Industrial (-40°C to 85°C) |
| | | | AT27C011-25DM AT27C011-25LM | 28DW6 32LW | Military (-55°C to 125°C) |
| | | | AT27C011-25DM/883 AT27C011-25LM/883 | 28DW6 32LW | Military/883C Class B, Fully Compliant (-55°C to 125°C) |

Ordering Information

| Package Type | |
|--------------|--|
| 28DW6 | 28 Lead, 0.600" Wide, Windowed, Ceramic Dual Inline Package (Cerdip) |
| 32J | 32 Lead, Plastic J-Leaded Chip Carrier OTP (PLCC) |
| 32LW | 32 Pad, Windowed, Ceramic Leadless Chip Carrier (LCC) |
| 28P6 | 28 Lead, 0.600" Wide, Plastic Dual Inline Package OTP (PDIP) |

